

## RAD-HARD OCTAL D-TYPE LATCH WITH 3 STATE OUTPUT NON INVERTING

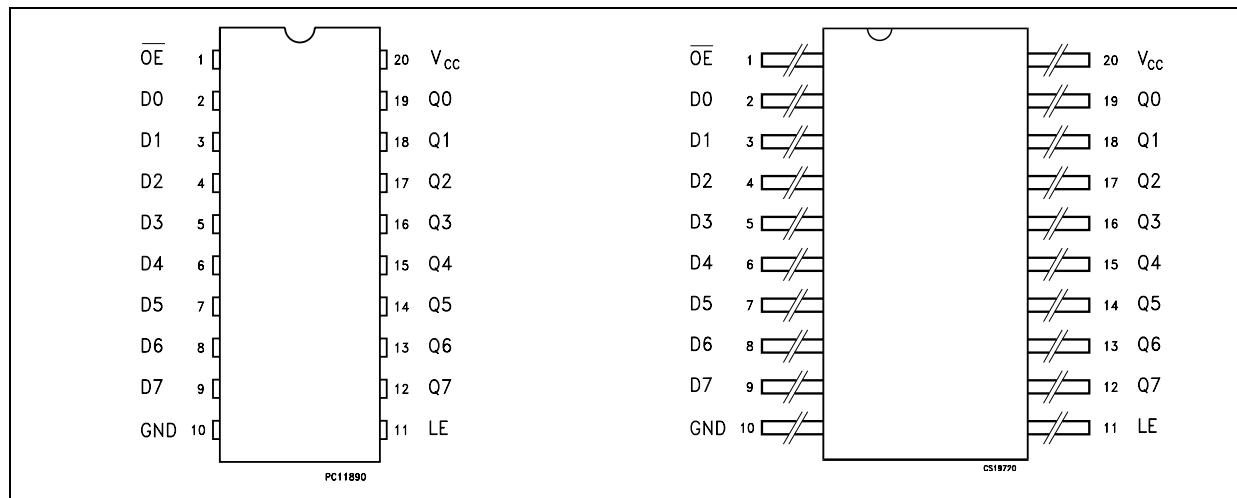
- HIGH SPEED:  
 $t_{PD} = 13\text{ns}$  (TYP.) at  $V_{CC} = 6\text{V}$
- LOW POWER DISSIPATION:  
 $I_{CC} = 4\mu\text{A}$ (MAX.) at  $T_A=25^\circ\text{C}$
- HIGH NOISE IMMUNITY:  
 $V_{NIH} = V_{NIL} = 28\% V_{CC}$  (MIN.)
- SYMMETRICAL OUTPUT IMPEDANCE:  
 $|I_{OHI}| = I_{OL} = 6\text{mA}$  (MIN)
- BALANCED PROPAGATION DELAYS:  
 $t_{PLH} \approx t_{PHL}$
- WIDE OPERATING VOLTAGE RANGE:  
 $V_{CC}$  (OPR) = 2V to 6V
- PIN AND FUNCTION COMPATIBLE WITH 54 SERIES 573
- SPACE GRADE-1: ESA SCC QUALIFIED
- 50 krad QUALIFIED, 100 krad AVAILABLE ON REQUEST
- NO SEL UNDER HIGH LET HEAVY IONS IRRADIATION
- DEVICE FULLY COMPLIANT WITH SCC-9202-072

### DESCRIPTION

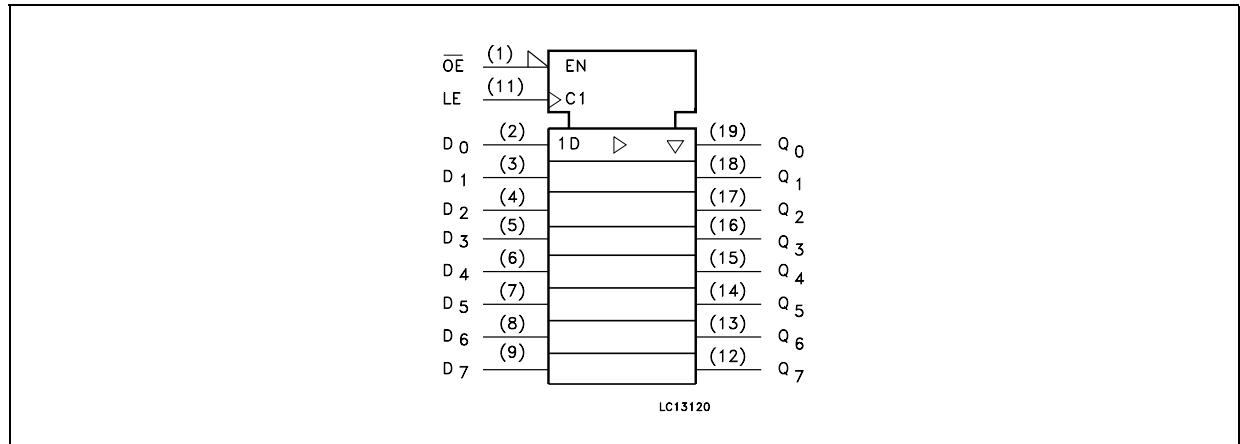
The M54HC573 is an high speed CMOS OCTAL LATCH WITH 3-STATE OUTPUTS fabricated with silicon gate C<sup>2</sup>MOS technology.

This 8-BIT D-Type latches is controlled by a latch enable input (LE) and output enable input (OE).

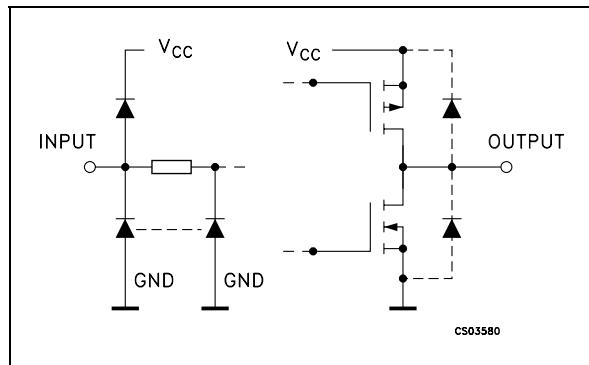
### PIN CONNECTION



**Figure 1: IEC Logic Symbols**



**Figure 2: Input And Output Equivalent Circuit**



**Table 1: Pin Description**

PIN N°	SYMBOL	NAME AND FUNCTION
1	OE	3 State Output Enable Input (Active LOW)
2, 3, 4, 5, 6, 7, 8, 9	D0 to D7	Data Inputs
12, 13, 14, 15, 16, 17, 18, 19	Q0 to Q7	3 State Latch Outputs
11	LE	Latch Enable Input
10	GND	Ground (0V)
20	V <sub>CC</sub>	Positive Supply Voltage

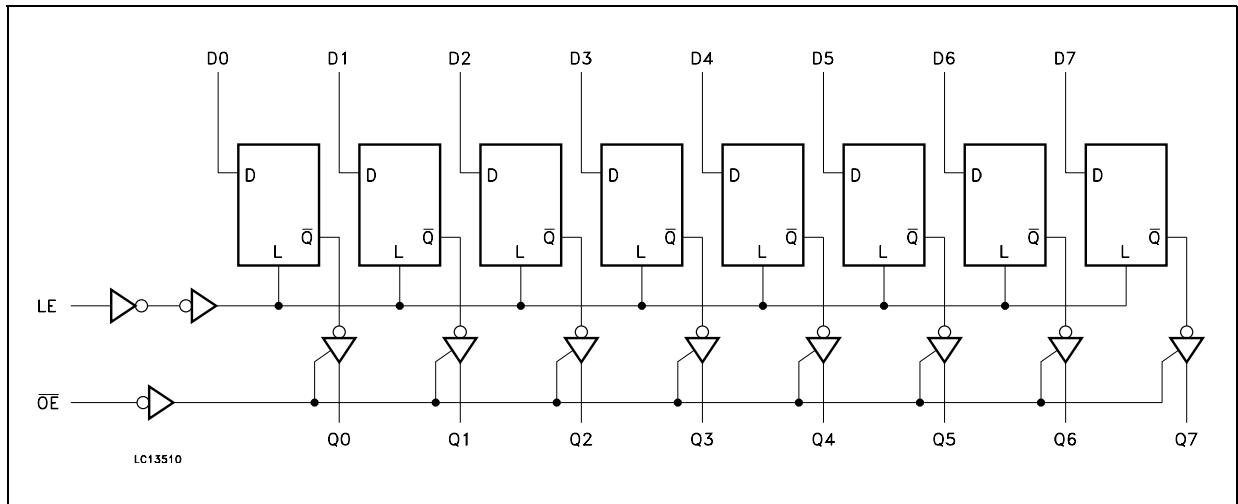
**Table 2: Truth Table**

INPUTS			OUTPUTS
OE	LE	D	Q
H	X	X	Z
L	L	X	NO CHANGE (*)
L	H	L	L
L	H	H	H

X: Don't Care

Z: High Impedance

(\*): Q Outputs are latched at the time when the LE input is taken low logic level.

**Figure 3: Logic Diagram****Table 3: Absolute Maximum Ratings**

Symbol	Parameter	Value	Unit
$V_{CC}$	Supply Voltage	-0.5 to +7	V
$V_I$	DC Input Voltage	-0.5 to $V_{CC} + 0.5$	V
$V_O$	DC Output Voltage	-0.5 to $V_{CC} + 0.5$	V
$I_{IK}$	DC Input Diode Current	$\pm 20$	mA
$I_{OK}$	DC Output Diode Current	$\pm 20$	mA
$I_O$	DC Output Current	$\pm 35$	mA
$I_{CC}$ or $I_{GND}$	DC $V_{CC}$ or Ground Current	$\pm 70$	mA
$P_D$	Power Dissipation	420	mW
$T_{stg}$	Storage Temperature	-65 to +150	°C
$T_L$	Lead Temperature (10 sec)	265	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied.

**Table 4: Recommended Operating Conditions**

Symbol	Parameter	Value	Unit	
$V_{CC}$	Supply Voltage	2 to 6	V	
$V_I$	Input Voltage	0 to $V_{CC}$	V	
$V_O$	Output Voltage	0 to $V_{CC}$	V	
$T_{op}$	Operating Temperature	-55 to 125	°C	
$t_r, t_f$	Input Rise and Fall Time	$V_{CC} = 2.0V$	0 to 1000	ns
		$V_{CC} = 4.5V$	0 to 500	ns
		$V_{CC} = 6.0V$	0 to 400	ns

Table 5: DC Specifications

Symbol	Parameter	Test Condition		Value						Unit	
		$V_{CC}$ (V)		$T_A = 25^\circ C$			$-40 \text{ to } 85^\circ C$		$-55 \text{ to } 125^\circ C$		
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
$V_{IH}$	High Level Input Voltage	2.0		1.5			1.5		1.5		V
		4.5		3.15			3.15		3.15		
		6.0		4.2			4.2		4.2		
$V_{IL}$	Low Level Input Voltage	2.0				0.5		0.5		0.5	V
		4.5				1.35		1.35		1.35	
		6.0				1.8		1.8		1.8	
$V_{OH}$	High Level Output Voltage	2.0	$I_O=-20 \mu A$	1.9	2.0		1.9		1.9		V
		4.5	$I_O=-20 \mu A$	4.4	4.5		4.4		4.4		
		6.0	$I_O=-20 \mu A$	5.9	6.0		5.9		5.9		
		4.5	$I_O=-6.0 mA$	4.18	4.31		4.13		4.10		
		6.0	$I_O=-7.8 mA$	5.68	5.8		5.63		5.60		
$V_{OL}$	Low Level Output Voltage	2.0	$I_O=20 \mu A$		0.0	0.1		0.1		0.1	V
		4.5	$I_O=20 \mu A$		0.0	0.1		0.1		0.1	
		6.0	$I_O=20 \mu A$		0.0	0.1		0.1		0.1	
		4.5	$I_O=6.0 mA$		0.17	0.26		0.33		0.40	
		6.0	$I_O=7.8 mA$		0.18	0.26		0.33		0.40	
$I_I$	Input Leakage Current	6.0	$V_I = V_{CC} \text{ or GND}$			$\pm 0.1$		$\pm 1$		$\pm 1$	$\mu A$
$I_{OZ}$	High Impedance Output Leakage Current	6.0	$V_I = V_{IH} \text{ or } V_{IL}$ $V_O = V_{CC} \text{ or GND}$			$\pm 0.5$		$\pm 5$		$\pm 10$	$\mu A$
$I_{CC}$	Quiescent Supply Current	6.0	$V_I = V_{CC} \text{ or GND}$			4		40		80	$\mu A$

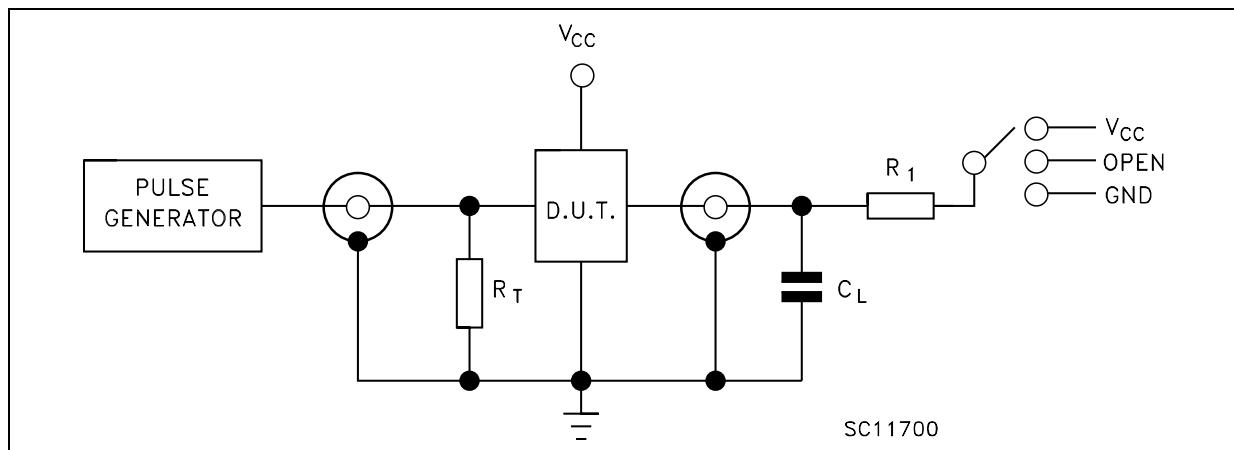
**Table 6: AC Electrical Characteristics ( $C_L = 50 \text{ pF}$ , Input  $t_r = t_f = 6\text{ns}$ )**

Symbol	Parameter	Test Condition			Value						Unit	
		$V_{CC}$ (V)	$C_L$ (pF)		$T_A = 25^\circ\text{C}$			$-40 \text{ to } 85^\circ\text{C}$		$-55 \text{ to } 125^\circ\text{C}$		
					Min.	Typ.	Max.	Min.	Max.	Min.		
$t_{TLH} t_{THL}$	Output Transition Time	2.0	50			25	60		75		90	ns
		4.5				7	12		15		18	
		6.0				6	10		13		15	
$t_{PLH} t_{PHL}$	Propagation Delay Time (LE - Q)	2.0	50			50	115		145		175	ns
		4.5				15	23		29		35	
		6.0				13	20		25		30	
		2.0	150			60	155		195		235	ns
		4.5				20	31		39		47	
		6.0				17	26		33		40	
$t_{PLH} t_{PHL}$	Propagation Delay Time (D - Q)	2.0	50			42	110		140		165	ns
		4.5				14	22		28		33	
		6.0				12	19		24		28	
		2.0	150			57	150		190		225	ns
		4.5				19	30		38		45	
		6.0				16	26		32		38	
$t_{PZL} t_{PZH}$	High Impedance Output Enable Time	2.0	50	$R_L = 1 \text{ k}\Omega$		55	140		175		210	ns
		4.5				17	28		35		42	
		6.0				14	24		30		36	
		2.0	150	$R_L = 1 \text{ k}\Omega$		66	180		225		270	ns
		4.5				22	36		45		54	
		6.0				19	31		38		46	
$t_{PLZ} t_{PHZ}$	High Impedance Output Disable Time	2.0	50	$R_L = 1 \text{ k}\Omega$		40	125		155		190	ns
		4.5				17	25		31		38	
		6.0				15	21		26		32	
$t_{W(L)} t_{W(H)}$	Minimum Pulse Width	2.0	50			40	75		95		110	ns
		4.5				8	15		19		22	
		6.0				7	13		16		19	
$t_s$	Minimum Set-up Time	2.0	50			16	50		65		75	ns
		4.5				5	10		13		15	
		6.0				3	9		11		13	
$t_h$	Minimum Hold Time	2.0	50				5		5		5	ns
		4.5					5		5		5	
		6.0					5		5		5	

**Table 7: Capacitive Characteristics**

Symbol	Parameter	Test Condition			Value						Unit
		V <sub>CC</sub> (V)				T <sub>A</sub> = 25°C			-40 to 85°C		Unit
			Min.	Typ.	Max.	Min.	Max.	Min.	Max.	Min.	
C <sub>IN</sub>	Input Capacitance					5	10		10		pF
C <sub>OUT</sub>	Output Capacitance					10					pF
C <sub>PD</sub>	Power Dissipation Capacitance (note 1)					51					pF

1) C<sub>PD</sub> is defined as the value of the IC's internal equivalent capacitance which is calculated from the operating current consumption without load. (Refer to Test Circuit). Average operating current can be obtained by the following equation. I<sub>CC(opr)</sub> = C<sub>PD</sub> × V<sub>CC</sub> × f<sub>IN</sub> + I<sub>CC</sub>/8 (per Flip Flop) and the C<sub>PD</sub> when n pcs of Flip Flop operate, can be gained by the following equation: C<sub>PD(TOTAL)</sub> = 33 + 18 × n (pF)

**Figure 4: Test Circuit**

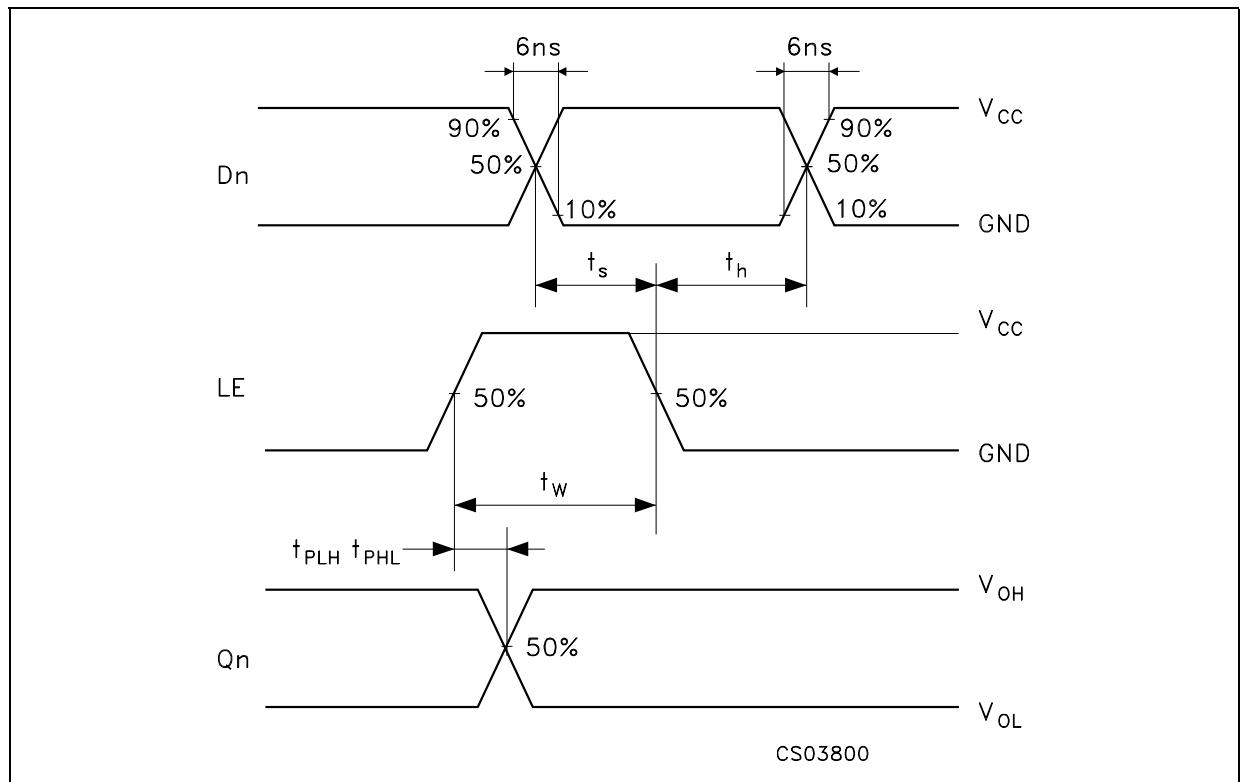
TEST	SWITCH
t <sub>PLH</sub> , t <sub>PHL</sub>	Open
t <sub>PZL</sub> , t <sub>PLZ</sub>	V <sub>CC</sub>
t <sub>PZH</sub> , t <sub>PHZ</sub>	GND

C<sub>L</sub> = 50pF/150pF or equivalent (includes jig and probe capacitance)

R<sub>1</sub> = 1KΩ or equivalent

R<sub>T</sub> = Z<sub>OUT</sub> of pulse generator (typically 50Ω)

**Figure 5: Waveform - LE To Qn Propagation Delays, LE Minimum Pulse Width, Dn To LE Setup And Hold Times (f=1MHz; 50% duty cycle)**



**Figure 6: Waveform - Output Enable And Disable Times (f=1MHz; 50% duty cycle)**

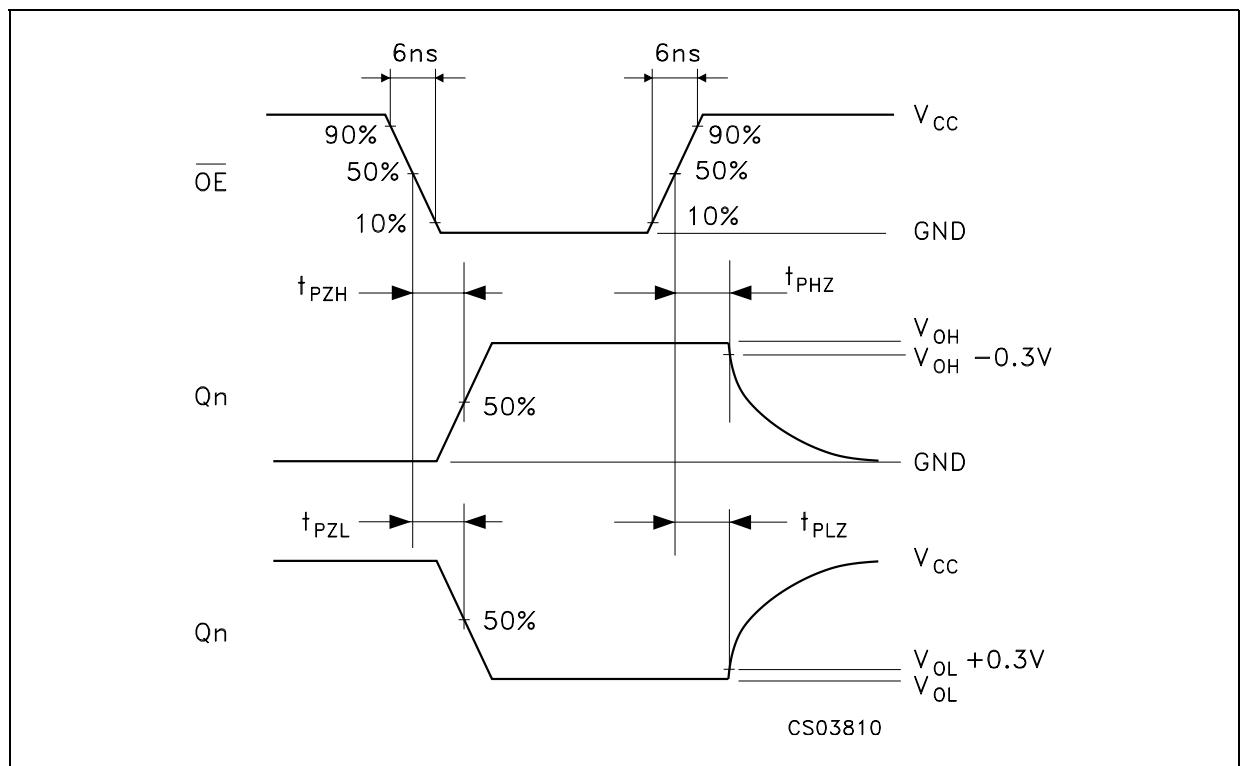
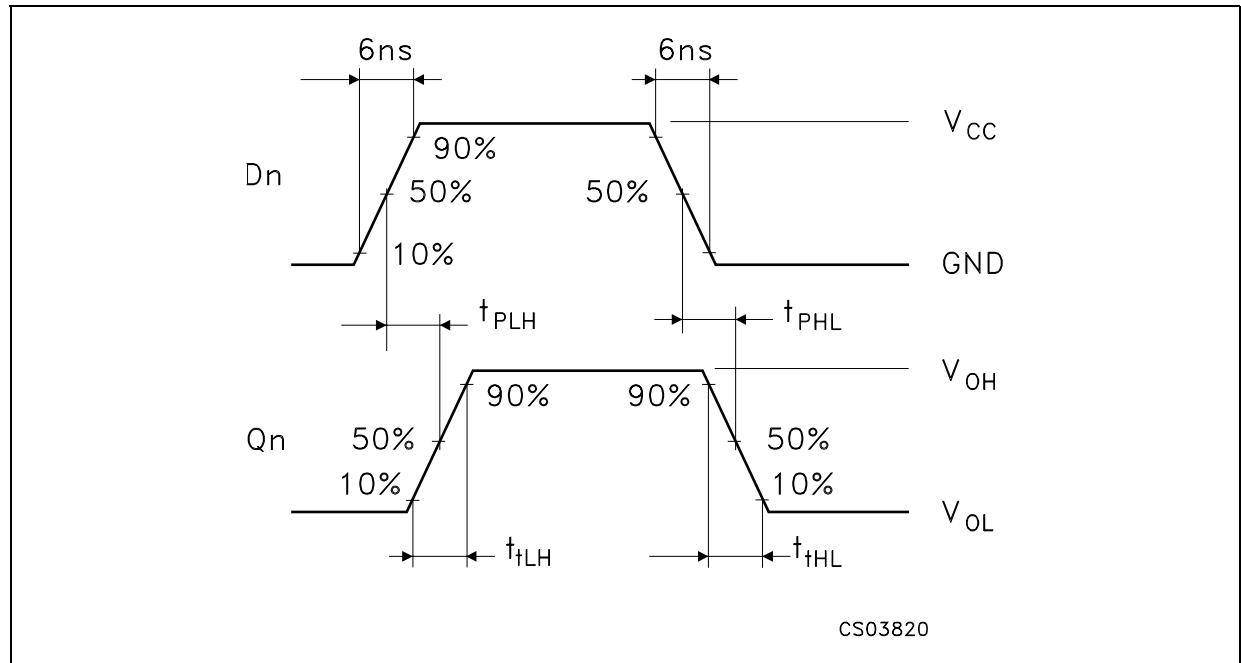
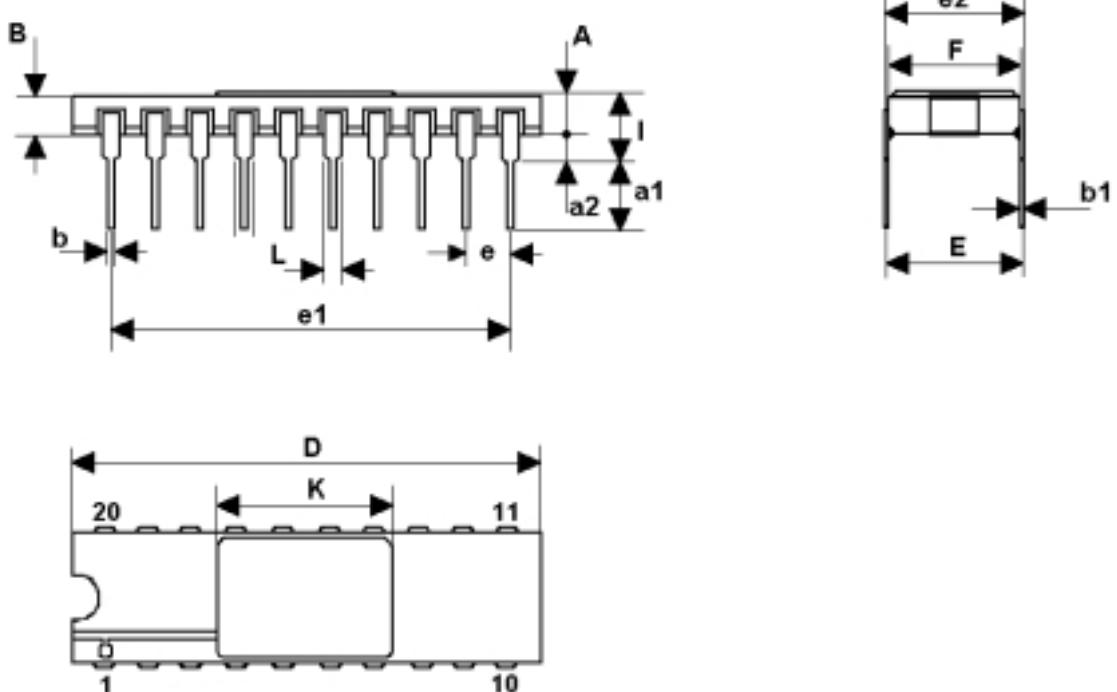


Figure 7: Waveform - Propagation Delay Times (f=1MHz; 50% duty cycle)



## DILC-20 MECHANICAL DATA

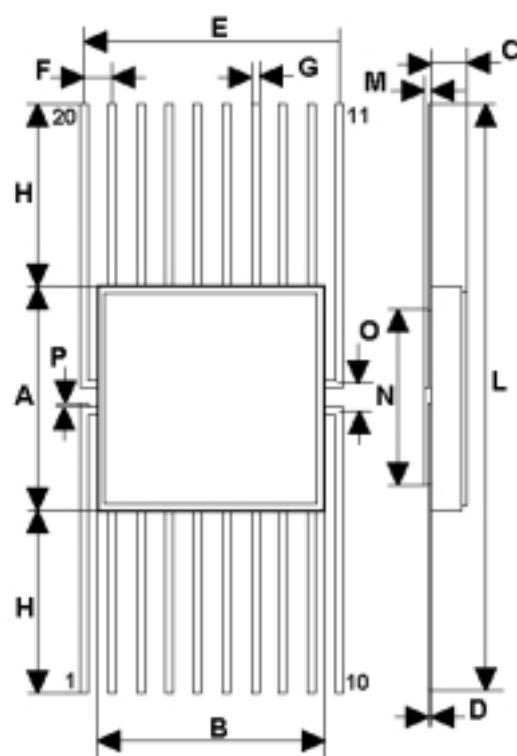
DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A	2.1		2.71	0.083		0.107
a1	3.00		3.70	0.118		0.146
a2	0.63	0.88	1.14	0.025	0.035	0.045
B	1.93	2.03	2.23	0.076	0.080	0.088
b	0.40	0.45	0.50	0.016	0.018	0.020
b1	0.20	0.254	0.30	0.008	0.010	0.012
D	25.14	25.40	25.65	0.990	1.000	1.010
E	7.36	7.62	7.87	0.290	0.300	0.310
e		2.54			0.100	
e1	22.73	22.86	22.99	0.895	0.900	0.905
e2	7.62	7.87	8.12	0.300	0.310	0.320
F	7.29	7.49	7.70	0.287	0.295	0.303
I			3.86			0.152
K	11.30		11.56	0.445		0.455
L	1.14	1.27	1.40	0.045	0.050	0.055



0016178J

## FPC-20 MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A	9.98	10.16	10.34	0.393	0.400	0.407
B	9.98	10.16	10.34	0.393	0.400	0.407
C	1.45	1.61	1.78	0.57	0.63	0.070
D	0.10	0.127	0.18	0.004	0.005	0.007
E	11.30	11.43	11.56	0.445	0.450	0.455
F		1.27			0.050	
G	0.38	0.43	0.48	0.015	0.017	0.019
H	7.24		8.16	0.285		0.320
L	24.46		26.67	0.960		1.050
M	0.45	0.50	0.55	0.018	0.020	0.022
N		7.87			0.310	
O	1.14	1.27	1.40	0.045	0.050	0.055
P	0.10	0.18	0.25	0.004	0.007	0.010



**Table 8: Revision History**

Date	Revision	Description of Changes
14-May-2004	1	First Release

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